

FEI Tecnai G2 F30 for Materials Science TEM



The Tecnai G2 transmission electron microscope unifies fast, efficient and easy operation with proven reliability to serve many applications needs – from basic, rapid sample screening to unique, sophisticated experiments requiring superior analytical capabilities. Providing excellent imaging performance, the Tecnai G2 enables high resolution imaging and diffraction data in uncorrected S/TEM. With its high tilt range, automation and dynamic focus adjustment, characterizing it as a TEM with outstanding analytical versatility, Tecnai G2 supports a wide range of techniques including high resolution S/TEM, diffraction, chemical analysis and 3D tomography. The unique field emission gun registry and customizable settings for critical instrument parameters ensure quick results and efficient use management. This accelerates productivity in your multi-user facility, without sacrificing the quality imaging you demand from your daily work.

Rating: Not Rated Yet

Price

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